JH TECHNOLOGIES™

Feature/Specification	CX-200K	CX-200Plus
Magnification	9x to 500,000x	15x to 300,000x
Spatial Resolution	<3nm	<3nm at 30kV
Detectors	SE, BSE (Standard), Optional EDS, EBSD, STEM	SE, BSE (Standard), Optional EDS, STEM
Imaging Modes	Auto Focus, Auto Brightness & Contrast, Panorama v2	Auto Focus, Auto Brightness & Contrast, Panorama v2
Vacuum Modes	High Vacuum (HV), Low Vacuum (LV 20Pa), Variable Pressure (VP 10, 20, 30Pa)	High Vacuum (HV)
Electron Source	Tungsten Filament	Tungsten Filament
Accelerating Voltage	1 – 30kV	1 – 30kV (adjustable in 1kV scale)
Sample Stage	X: 60mm, Y: 60mm, Z: 60mm, R: 360º, T: 20º to 90º	X: 60mm, Y: 60mm, Z: 60mm, T: -20º to 90º, R: 360º

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Feature/Specification	CX-200K	CX-200Plus
Sample Size	Up to 160mm in diameter	Up to 160mm in diameter
Stage Automation	Manual and motorized control of X, Y, Z, R, T axes	Manual and motorized control of X, Y, Z, R, T axes
Optional Features	EDS (Oxford, Bruker), EBSD, STEM, CoolStage, Nanofiber Scanner, Air-protection module	STEM, CoolStage, EDS (Oxford, Bruker)
Data Output Formats	JPG, TIFF, BMP	JPG, TIFF, BMP
Dimensions	640(W) × 682(L) × 1,432(H) mm	640(W) × 682(L) × 1,430(H) mm
Weight	200kg	230kg
Ideal Applications	Research, Failure Analysis, Battery Research	Research, Failure Analysis, Quality Control